Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	,
10/810,894	FUJII ET AL.	
Examiner	Art Unit	
Philip H. Leung	3742	

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	SEAR	CHED	
Class	Subclass	Date	Examiner
219	619, 670, 661-663 672-676	6/9/2005	P.L.
399	328-338		
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Class	Subclass	Date	Examiner
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